Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/749,045	CHEN ET AL.	
Examiner	Art Unit	
Mathieu D. Vargot	1732	

	SEARCHED					
Class	Subclass	Date	Examiner			
264	1.1,1.24					
	1.31, 2.5					
425	808,					
	810	9/29/06	avv			
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INTERFERENCE SEARCHED				
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